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Application/Control No.	Applicant(s)/Patent under Reexamination
09/876,183	CHANG ET AL.
Examiner	Art Unit
Hai L. Nguyen	2816

	SEAR	CHED	
Class	Subclass	Date	Examiner
327	2,3,5, 7-9,12	4/18/2005	HLN]
	238,244		
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Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH)
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